



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Wallace T.Y. Tang
Serial No. : 09/134,147
Filed : August 14, 1998
Title : IN-SITU REAL-TIME MONITORING TECHNIQUE AND APPARATUS FOR
DETECTION OF THIN FILMS DURING CHEMICAL/MECHANICAL
POLISHING PLANARIZATION

Art Unit : 1763
Examiner : Sylvia R. MacArthur

MAIL STOP AMENDMENT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Copies of the references listed on the attached form PTO-1449 are enclosed.

This statement is being filed after a first Office action on the merits, but before receipt of a final Office action or a Notice of Allowance. A check for \$180 in payment of the late submission fee of §1.17(p) is enclosed. Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 11/12/04

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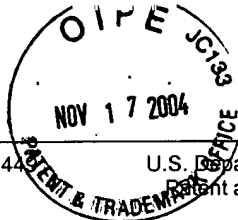
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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 05542-459003	Application No. 09/134,147
		Applicant Wallace T.Y. Tang	
		Filing Date August 14, 1998	Group Art Unit 1763

**Information Disclosure Statement
by Applicant**
(Use several sheets if necessary)

(37 CFR §1.98(b))

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
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	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL	KR 92-20600	11/1992	KR			Partial Translation	
	AM	JP 60-79304	05/1985	JP			Partial Translation	
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

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EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	